

PRODUCT TECHNICAL BRIEF

KYKY EM-8100 High-Resolution Field-Emission SEM

KYKY EM-8100 High-Resolution Field-Emission SEM - LeakLab solutions for leak testing, vacuum systems and test equipment.

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Technical Data

PARAMETER	PUBLISHED VALUE / INFORMATION
SE resolution	0.9 nm at 30 kV
Accelerating voltage	0.2-30 kV
Magnification	1×-3,000,000×; optical navigation 1×-100×
Electron source	Schottky field-emission gun
Stage	Five-axis motorized large-specimen stage with collision warning
Standard imaging listed by KYKY	High-vacuum SE, chamber camera and optical navigation
Optional detector listed by KYKY	Four-segment semiconductor BSE
Options	EDS, EBSD, STEM, CL, load lock, heating, cooling and tensile stages

Technical and Project Information

Schottky field-emission scanning electron microscope with 0.9 nm SE resolution at 30 kV, 0.2-30 kV accelerating voltage, magnification to 3,000,000× and a large five-axis motorized stage.

The EM-8100 uses a Schottky field-emission source, low-aberration objective and beam-acceleration design for high-resolution imaging over a wide accelerating-voltage range.

Final resolution is specified at defined accelerating voltage, working distance, probe current and specimen conditions. Confirm detector package, chamber ports, stage travel, utilities, vibration and electromagnetic-site criteria, analysis software and acceptance sample.

- Helium Reference Leaks
- Scanning Electron Microscopes
- Leak-Detector Accessories

WORLDWIDE PROJECT CONTACT

Send the test object or system, operating conditions, target sensitivity or pressure range, applicable standard, destination country, quantity and schedule. LeakLab will review the project scope.

mail@leaklab.org

Regarding: KYKY EM-8100 High-Resolution Field-Emission SEM

Specifications, standards, verification scope, availability and commercial terms must be confirmed for the exact configuration and destination jurisdiction before order or project acceptance.